

规格书编号

**SPEC NO: HDF549.5E5S4SP00**

# 产品规格书

# SPECIFICATION

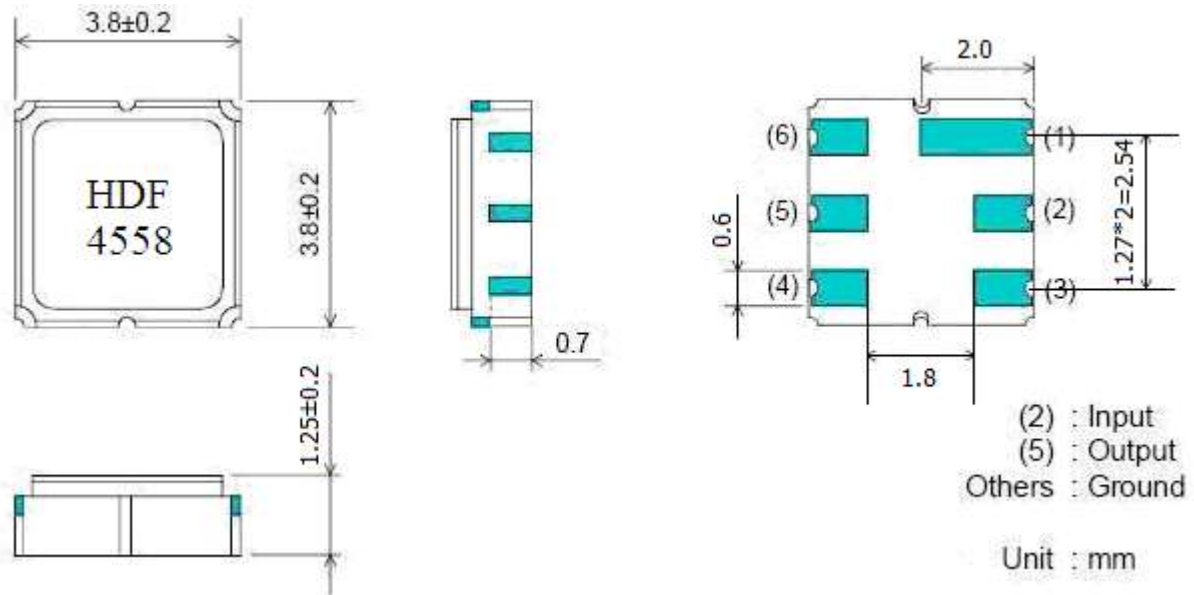
CUSTOMER 客户: \_\_\_\_\_  
PRODUCT 产品: \_\_\_\_\_ SAW FILTER \_\_\_\_\_  
MODEL NO 型号: \_\_\_\_\_ HDF549.5E5-S4 \_\_\_\_\_  
MARKING 印字: \_\_\_\_\_ HDF4558 \_\_\_\_\_  
PREPARED 编制: \_\_\_\_\_ CHECKED 审核: \_\_\_\_\_  
APPROVED 批准: \_\_\_\_\_ D A T E 日期: \_\_\_\_\_ 2015-3-5 \_\_\_\_\_

客户确认 CUSTOMER RECEIVED:		
审核 CHECKED	批准 APPROVED	日期 DATE

无锡市好达电子有限公司  
Shoulder Electronics Limited



## 1. Package Dimension



## 2. Performance

### 2.1 Maximum Rating

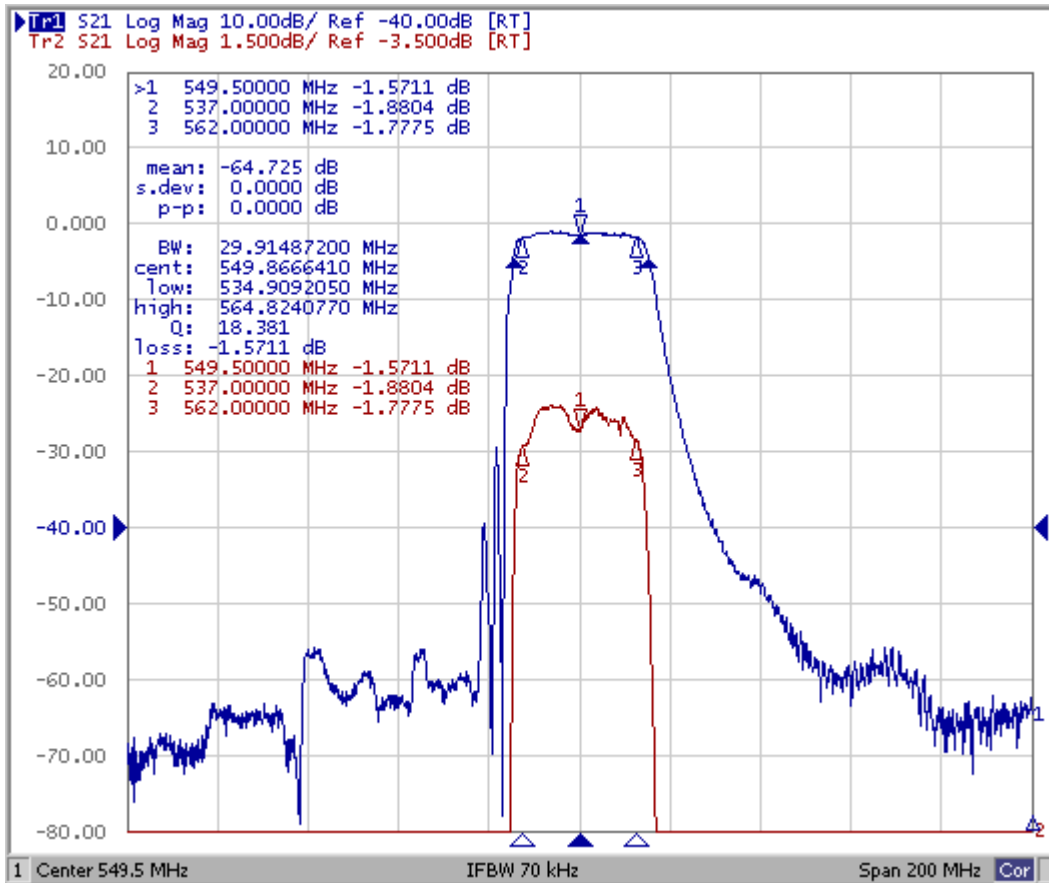
Items	Rating	unit
Maximum Working Voltage	10	V <sub>dc</sub>
Maximum Working Power	10	dBm
Operating Temperature Range	-40 ~ +85	°C
Storage Temperature Range	-40 ~ +85	°C

### 2.2 Electronic Characteristics

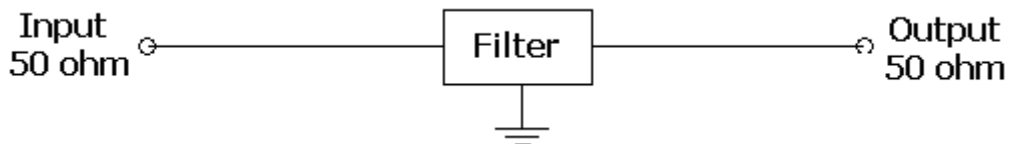
( at 25°C ± 5°C )

	Unit	Minimum	Typical	Maximum
Center Frequency Fc	MHz	547.5	549.5	551.5
Insertion Loss (549.5 MHz )	dB		1.5	3.0
-1dB bandwidth	MHz	25	29.9	-
Attenuation				
DC~520 MHz	dB	45	55	-
600~1000 MHz		45	55	
Input/Output Impedance	Ohms		50	

**2.3 Frequency Characteristics**



**3. Test Circuit**



**4. ENVIRONMENTAL CHARACTERISTICS**

**4.1 High temperature exposure**

Subject the device to +85°C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2-2.

**4.2 Low temperature exposure**

Subject the device to -40°C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2-2.

**4.3 Temperature cycling**

Subject the device to a low temperature of -40°C for 30 minutes. Following by a high temperature of +85°C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2-2.

**4.4 Resistance to solder heat**

Dip the device terminals no closer than 1.5mm into the solder bath at 260°C ±10°C for

10±1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2-2.

#### 4.5 Solderability

Subject the device terminals into the solder bath at 245°C ±5°C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2-2.

#### 4.6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2-2.

#### 4.7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2-2.

## 5. REMARK

### 5.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

### 5.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

### 5.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.